

Date Created : 2007/11/27
 Date Issued On : 2007/12/19
 PCN# : Q4074804

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Implementation of change:
 Expected 1st Device Shipment Date: 2008/03/14

Earliest Year/Work Week of Changed Product: 0811

Change Type Description: Alternate Fab Location

Description of Change (From): Fairchild Semiconductor 8-inch wafer fabrication line located in Mountaintop, Pennsylvania.

Description of Change (To): Fairchild Semiconductor QS 9000 approved 6-inch facility for wafer fabrication located in Bucheon, Korea.

Reason for Change : To provide an alternative wafer fabrication location.

Qual/REL Plan Numbers : Q20070283

Qualification :

To qualify an alternate Fairchild's 6-inch fabrication located in Bucheon for selected products in TO220, TO247, TO252, TO262, TO263, TT220, and XSWFR packages.

Results/Discussion

Test: (Autoclave)					
Lot	Device	96-HOURS	Failure Code		
Q20070283AAACLV	FDD2572	0/77			
Q20070283BAACLV	FDB2532	0/77			
Q20070283CAACLV	FDP2532	0/77			
Q20070283DAACLV	FDH038AN08A1	0/77			
Test: (High Humidity, High Temp, Rev. Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070283AAH3TRB	FDD2572	0/77			

			0/77		
				0/77	
Q20070283BAH3TRB	FDB2532	0/77			
			0/77		
				0/77	
Q20070283CAH3TRB	FDP2532	0/77			
			0/77		
				0/77	
Q20070283DAH3TRB	FDH038AN08A1	0/77			
			0/77		
				0/77	

Test: (High Temperature Gate Bias)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070283AAHTGB	FDD2572	0/77			
			0/77		
				0/77	
Q20070283BAHTGB	FDB2532	0/77			
			0/77		
				0/77	
Q20070283CAHTGB	FDP2532	0/77			
			0/77		
				0/77	
Q20070283DAHTGB	FDH038AN08A1	0/77			
			0/77		
				0/77	

Test: (High Temperature Reverse Bias)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070283AAHTRB	FDD2572	0/77			
			0/77		
				0/77	
Q20070283BAHTRB	FDB2532	0/77			
			0/77		
				0/77	
Q20070283CAHTRB	FDP2532	0/77			
			0/77		
				0/77	
Q20070283DAHTRB	FDH038AN08A1	0/77			
			0/77		
				0/77	

Test: (Power Cycle)

Lot	Device	5000-CYCLES	10000-CYCLES	15000-CYCLES	Failure Code
Q20070283AAPRCL	FDD2572	0/77			
			0/77		
				0/77	

Test: -55, 150C (Temperature Cycle)

Lot	Device	100-CYCLES	500-CYCLES	1000	Failure Code
Q20070283DATMCL3	FDH038AN08A1	0/77			
			0/77		
				0/77	

Test: -65C, 150C (Temperature Cycle)

Lot	Device	100-CYCLES	500-CYCLES	1000	Failure Code
Q20070283AATMCL1	FDD2572	0/77			
			0/77		
				0/77	
Q20070283BATMCL1	FDB2532	0/77			
			0/77		
				0/77	
Q20070283CATMCL1	FDP2532	0/77			
			0/77		
				0/77	

Test: MSL(1), PKG(Small), PeakTemp(260c), Cycles(3) (Precondition)

Lot	Device	Results	Failure Code
Q20070283AAPCNL1A	FDD2572	0/308	
Q20070283BAPCNL1A	FDB2532	0/308	

Test: Medium Size Pkg's (TO-220, D2) (Power Cycle)

Lot	Device	3000-CYCLE	3000-CYCLE	5000-CYCLE	3572-CYCLE	Failure Code
Q20070283BAPRCL1	FDB2532		0/77			
					0/77	
Q20070283CAPRCL1	FDP2532		0/77			
					0/77	
Q20070283DAPRCL1	FDH038AN08A1	0/77				
				0/77		

Product Id Description : Fairchild Semiconductor's selected FDBxxx, FDDxxx, FDHxxx, FDIxxx, FDPxxx, and PFCPxxx products currently manufactured using Fairchild's 8-inch fabrication process in Mountain Top, PA. Please refer to the affected FSID list.

Affected FSIDs :

FDB2532	FDB3632	FDB3632_F101
FDB3652	FDB3672	FDB42AN15A0
FDB5800	FDD120AN15A0	FDH3632
FDI3652	FDP2532	FDP2552
FDP2572	FDP3632	FDP3651U
FDP3652	FDP3672	FDP3682
FDP42AN15A0	PCF2532W_R4800	PCF3632W_R4800